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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details

Product Status	Obsolete
Number of LABs/CLBs	4964
Number of Logic Elements/Cells	118143
Total RAM Bits	8315904
Number of I/O	372
Number of Gates	-
Voltage - Supply	0.87V ~ 0.93V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	780-BBGA, FCBGA
Supplier Device Package	780-FBGA (29x29)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep2agx125ef29c5n

Recommended Operating Conditions

This section lists the functional operation limits for AC and DC parameters for Arria II GX and GZ devices. All supplies are required to monotonically reach their full-rail values without plateaus within t_{RAMP} .

Table 1–5 lists the recommended operating conditions for Arria II GX devices.

Table 1–5. Recommended Operating Conditions for Arria II GX Devices (Note 1) (Part 1 of 2)

Symbol	Description	Condition	Minimum	Typical	Maximum	Unit
V_{CC}	Supplies power to the core, periphery, I/O registers, PCIe HIP block, and transceiver PCS	—	0.87	0.90	0.93	V
V_{CCCB}	Supplies power to the configuration RAM bits	—	1.425	1.50	1.575	V
V_{CCBAT} (2)	Battery back-up power supply for design security volatile key registers	—	1.2	—	3.3	V
V_{CCPD} (3)	Supplies power to the I/O pre-drivers, differential input buffers, and MSEL circuitry	—	3.135	3.3	3.465	V
		—	2.85	3.0	3.15	V
		—	2.375	2.5	2.625	V
V_{CCIO}	Supplies power to the I/O banks (4)	—	3.135	3.3	3.465	V
		—	2.85	3.0	3.15	V
		—	2.375	2.5	2.625	V
		—	1.71	1.8	1.89	V
		—	1.425	1.5	1.575	V
		—	1.14	1.2	1.26	V
V_{CCD_PLL}	Supplies power to the digital portions of the PLL	—	0.87	0.90	0.93	V
V_{CCA_PLL}	Supplies power to the analog portions of the PLL and device-wide power management circuitry	—	2.375	2.5	2.625	V
V_I	DC Input voltage	—	-0.5	—	3.6	V
V_O	Output voltage	—	0	—	V_{CCIO}	V
V_{CCA}	Supplies power to the transceiver PMA regulator	—	2.375	2.5	2.625	V
V_{CCL_GXB}	Supplies power to the transceiver PMA TX, PMA RX, and clocking	—	1.045	1.1	1.155	V
V_{CCH_GXB}	Supplies power to the transceiver PMA output (TX) buffer	—	1.425	1.5	1.575	V
T_J	Operating junction temperature	Commercial	0	—	85	°C
		Industrial	-40	—	100	°C

Table 1–11. OCT With and Without Calibration Specification for Arria II GX Device I/Os (*Note 1*) (Part 2 of 2)

Symbol	Description	Conditions (V)	Calibration Accuracy		Unit
			Commercial	Industrial	
50- Ω R_S 3.0, 2.5, 1.8, 1.5, 1.2	50- Ω series OCT with calibration	$V_{CCIO} = 3.0, 2.5,$ 1.8, 1.5, 1.2	± 10	± 10	%
100- Ω R_D 2.5	100- Ω differential OCT without calibration	$V_{CCIO} = 2.5$	± 30	± 30	%

Note to Table 1–11:

- (1) OCT with calibration accuracy is valid at the time of calibration only.

Table 1–12 lists the OCT termination calibration accuracy specifications for Arria II GZ devices.

Table 1–12. OCT with Calibration Accuracy Specifications for Arria II GZ Devices (*Note 1*)

Symbol	Description	Conditions (V)	Calibration Accuracy			Unit
			C2	C3,I3	C4,I4	
25- Ω R_S 3.0, 2.5, 1.8, 1.5, 1.2 (2)	25- Ω series OCT with calibration	$V_{CCIO} = 3.0, 2.5,$ 1.8, 1.5, 1.2	± 8	± 8	± 8	%
50- Ω R_S 3.0, 2.5, 1.8, 1.5, 1.2	50- Ω internal series OCT with calibration	$V_{CCIO} = 3.0, 2.5,$ 1.8, 1.5, 1.2	± 8	± 8	± 8	%
50- Ω R_T 2.5, 1.8, 1.5, 1.2	50- Ω internal parallel OCT with calibration	$V_{CCIO} = 2.5, 1.8,$ 1.5, 1.2	± 10	± 10	± 10	%
20- Ω , 40- Ω , and 60- Ω R_S 3.0, 2.5, 1.8, 1.5, 1.2 (3)	20- Ω , 40- Ω and 60- Ω R_S expanded range for internal series OCT with calibration	$V_{CCIO} = 3.0, 2.5,$ 1.8, 1.5, 1.2	± 10	± 10	± 10	%
25- Ω $R_{S_left_shift}$ 3.0, 2.5, 1.8, 1.5, 1.2	25- Ω $R_{S_left_shift}$ internal left shift series OCT with calibration	$V_{CCIO} = 3.0, 2.5,$ 1.8, 1.5, 1.2	± 10	± 10	± 10	%

Notes to Table 1–12:

- (1) OCT calibration accuracy is valid at the time of calibration only.
 (2) 25- Ω R_S is not supported for 1.5 V and 1.2 V in Row I/O.
 (3) 20- Ω R_S is not supported for 1.5 V and 1.2 V in Row I/O.

Table 1–17 lists the pin capacitance for Arria II GZ devices.

Table 1–17. Pin Capacitance for Arria II GZ Devices

Symbol	Description	Typical	Unit
C_{IOTB}	Input capacitance on the top and bottom I/O pins	4	pF
C_{IOLR}	Input capacitance on the left and right I/O pins	4	pF
C_{CLKTB}	Input capacitance on the top and bottom non-dedicated clock input pins	4	pF
C_{CLKLR}	Input capacitance on the left and right non-dedicated clock input pins	4	pF
C_{OUTFB}	Input capacitance on the dual-purpose clock output and feedback pins	5	pF
$C_{CLK1}, C_{CLK3}, C_{CLK8},$ and C_{CLK10}	Input capacitance for dedicated clock input pins	2	pF

Internal Weak Pull-Up and Weak Pull-Down Resistors

Table 1–18 lists the weak pull-up and pull-down resistor values for Arria II GX devices.

Table 1–18. Internal Weak Pull-up and Weak Pull-Down Resistors for Arria II GX Devices (Note 1)

Symbol	Description	Conditions	Min	Typ	Max	Unit
R_{PU}	Value of I/O pin pull-up resistor before and during configuration, as well as user mode if the programmable pull-up resistor option is enabled.	$V_{CCIO} = 3.3 V \pm 5\% \text{ (2)}$	7	25	41	kΩ
		$V_{CCIO} = 3.0 V \pm 5\% \text{ (2)}$	7	28	47	kΩ
		$V_{CCIO} = 2.5 V \pm 5\% \text{ (2)}$	8	35	61	kΩ
		$V_{CCIO} = 1.8 V \pm 5\% \text{ (2)}$	10	57	108	kΩ
		$V_{CCIO} = 1.5 V \pm 5\% \text{ (2)}$	13	82	163	kΩ
		$V_{CCIO} = 1.2 V \pm 5\% \text{ (2)}$	19	143	351	kΩ
R_{PD}	Value of TCK pin pull-down resistor	$V_{CCIO} = 3.3 V \pm 5\%$	6	19	29	kΩ
		$V_{CCIO} = 3.0 V \pm 5\%$	6	22	32	kΩ
		$V_{CCIO} = 2.5 V \pm 5\%$	6	25	42	kΩ
		$V_{CCIO} = 1.8 V \pm 5\%$	7	35	70	kΩ
		$V_{CCIO} = 1.5 V \pm 5\%$	8	50	112	kΩ

Notes to Table 1–18:

- (1) All I/O pins have an option to enable weak pull-up except configuration, test, and JTAG pins. The weak pull-down feature is only available for JTAG TCK.
- (2) Pin pull-up resistance values may be lower if an external source drives the pin higher than V_{CCIO} .

Table 1–19 lists the weak pull-up resistor values for Arria II GZ devices.

Table 1–19. Internal Weak Pull-Up Resistor for Arria II GZ Devices (Note 1), (2)

Symbol	Description	Conditions	Min	Typ	Max	Unit
R_{PU}	Value of the I/O pin pull-up resistor before and during configuration, as well as user mode if the programmable pull-up resistor option is enabled.	$V_{CCIO} = 3.0 \text{ V} \pm 5\% \text{ (3)}$	—	25	—	$\text{k}\Omega$
		$V_{CCIO} = 2.5 \text{ V} \pm 5\% \text{ (3)}$	—	25	—	$\text{k}\Omega$
		$V_{CCIO} = 1.8 \text{ V} \pm 5\% \text{ (3)}$	—	25	—	$\text{k}\Omega$
		$V_{CCIO} = 1.5 \text{ V} \pm 5\% \text{ (3)}$	—	25	—	$\text{k}\Omega$
		$V_{CCIO} = 1.2 \text{ V} \pm 5\% \text{ (3)}$	—	25	—	$\text{k}\Omega$

Notes to Table 1–19:

- (1) All I/O pins have an option to enable weak pull-up except configuration, test, and JTAG pins.
- (2) The internal weak pull-down feature is only available for the JTAG TCK pin. The typical value for this internal weak pull-down resistor is approximately 25 $\text{k}\Omega$.
- (3) Pin pull-up resistance values may be lower if an external source drives the pin higher than V_{CCIO} .

Hot Socketing

Table 1–20 lists the hot-socketing specification for Arria II GX and GZ devices.

Table 1–20. Hot Socketing Specifications for Arria II Devices

Symbol	Description	Maximum
$I_{IOPIN(DC)}$	DC current per I/O pin	300 μA
$I_{IOPIN(AC)}$	AC current per I/O pin	8 mA (1)
$I_{XCVRTX(DC)}$	DC current per transceiver TX pin	100 mA
$I_{XCVRRX(DC)}$	DC current per transceiver RX pin	50 mA

Note to Table 1–20:

- (1) The I/O ramp rate is 10 ns or more. For ramp rates faster than 10 ns, $|I_{IOPIN}| = C \frac{dv}{dt}$, in which “C” is I/O pin capacitance and “dv/dt” is slew rate.

Schmitt Trigger Input

The Arria II GX device supports Schmitt trigger input on the TDI, TMS, TCK, nSTATUS, nCONFIG, nCE, CONF_DONE, and DCLK pins. A Schmitt trigger feature introduces hysteresis to the input signal for improved noise immunity, especially for signals with slow edge rates.

Table 1–21 lists the hysteresis specifications across the supported V_{CCIO} range for Schmitt trigger inputs in Arria II GX devices.

Table 1–21. Schmitt Trigger Input Hysteresis Specifications for Arria II GX Devices

Symbol	Description	Condition (V)	Minimum	Unit
$V_{Schmitt}$	Hysteresis for Schmitt trigger input	$V_{CCIO} = 3.3$	220	mV
		$V_{CCIO} = 2.5$	180	mV
		$V_{CCIO} = 1.8$	110	mV
		$V_{CCIO} = 1.5$	70	mV

Table 1–26 lists the single-ended SSTL and HSTL I/O standard signal specifications for Arria II GX devices.

Table 1–26. Single-Ended SSTL and HSTL I/O Standard Signal Specifications for Arria II GX Devices

I/O Standard	V _{IL(DC)} (V)		V _{IH(DC)} (V)		V _{IL(AC)} (V)	V _{IH(AC)} (V)	V _{OL} (V)	V _{OH} (V)	I _{OL} (mA)	I _{OH} (mA)
	Min	Max	Min	Max	Max	Min	Max	Min		
SSTL-2 Class I	-0.3	V _{REF} - 0.18	V _{REF} + 0.18	V _{CCIO} + 0.3	V _{REF} - 0.35	V _{REF} + 0.35	V _{TT} - 0.57	V _{TT} + 0.57	8.1	-8.1
SSTL-2 Class II	-0.3	V _{REF} - 0.18	V _{REF} + 0.18	V _{CCIO} + 0.3	V _{REF} - 0.35	V _{REF} + 0.35	V _{TT} - 0.76	V _{TT} + 0.76	16.4	-16.4
SSTL-18 Class I	-0.3	V _{REF} - 0.125	V _{REF} + 0.125	V _{CCIO} + 0.3	V _{REF} - 0.25	V _{REF} + 0.25	V _{TT} - 0.475	V _{TT} + 0.475	6.7	-6.7
SSTL-18 Class II	-0.3	V _{REF} - 0.125	V _{REF} + 0.125	V _{CCIO} + 0.3	V _{REF} - 0.25	V _{REF} + 0.25	0.28	V _{CCIO} - 0.28	13.4	-13.4
SSTL-15 Class I	-0.3	V _{REF} - 0.1	V _{REF} + 0.1	V _{CCIO} + 0.3	V _{REF} - 0.175	V _{REF} + 0.175	0.2 × V _{CCIO}	0.8 × V _{CCIO}	8	-8
SSTL-15 Class II	-0.3	V _{REF} - 0.1	V _{REF} + 0.1	V _{CCIO} + 0.3	V _{REF} - 0.175	V _{REF} + 0.175	0.2 × V _{CCIO}	0.8 × V _{CCIO}	16	-16
HSTL-18 Class I	-0.3	V _{REF} - 0.1	V _{REF} + 0.1	V _{CCIO} + 0.3	V _{REF} - 0.2	V _{REF} + 0.2	0.4	V _{CCIO} - 0.4	8	-8
HSTL-18 Class II	-0.3	V _{REF} - 0.1	V _{REF} + 0.1	V _{CCIO} + 0.3	V _{REF} - 0.2	V _{REF} + 0.2	0.4	V _{CCIO} - 0.4	16	-16
HSTL-15 Class I	-0.3	V _{REF} - 0.1	V _{REF} + 0.1	V _{CCIO} + 0.3	V _{REF} - 0.2	V _{REF} + 0.2	0.4	V _{CCIO} - 0.4	8	-8
HSTL-15 Class II	-0.3	V _{REF} - 0.1	V _{REF} + 0.1	V _{CCIO} + 0.3	V _{REF} - 0.2	V _{REF} + 0.2	0.4	V _{CCIO} - 0.4	16	-16
HSTL-12 Class I	-0.15	V _{REF} - 0.08	V _{REF} + 0.08	V _{CCIO} + 0.15	V _{REF} - 0.15	V _{REF} + 0.15	0.25 × V _{CCIO}	0.75 × V _{CCIO}	8	-8
HSTL-12 Class II	-0.15	V _{REF} - 0.08	V _{REF} + 0.08	V _{CCIO} + 0.15	V _{REF} - 0.15	V _{REF} + 0.15	0.25 × V _{CCIO}	0.75 × V _{CCIO}	14	-14

Table 1–27 lists the single-ended SSTL and HSTL I/O standard signal specifications for Arria II GZ devices.

Table 1–27. Single-Ended SSTL and HSTL I/O Standards Signal Specifications for Arria II GZ Devices (Part 1 of 2)

I/O Standard	V _{IL(DC)} (V)		V _{IH(DC)} (V)		V _{IL(AC)} (V)	V _{IH(AC)} (V)	V _{OL} (V)	V _{OH} (V)	I _{OL} (mA)	I _{OH} (mA)
	Min	Max	Min	Max	Max	Min	Max	Min		
SSTL-2 Class I	-0.3	V _{REF} - 0.15	V _{REF} + 0.15	V _{CCIO} + 0.3	V _{REF} - 0.31	V _{REF} + 0.31	V _{TT} - 0.57	V _{TT} + 0.57	8.1	-8.1
SSTL-2 Class II	-0.3	V _{REF} - 0.15	V _{REF} + 0.15	V _{CCIO} + 0.3	V _{REF} - 0.31	V _{REF} + 0.31	V _{TT} - 0.76	V _{TT} + 0.76	16.2	-16.2
SSTL-18 Class I	-0.3	V _{REF} - 0.125	V _{REF} + 0.125	V _{CCIO} + 0.3	V _{REF} - 0.25	V _{REF} + 0.25	V _{TT} - 0.475	V _{TT} + 0.475	6.7	-6.7
SSTL-18 Class II	-0.3	V _{REF} - 0.125	V _{REF} + 0.125	V _{CCIO} + 0.3	V _{REF} - 0.25	V _{REF} + 0.25	0.28	V _{CCIO} - 0.28	13.4	-13.4
SSTL-15 Class I	—	V _{REF} - 0.1	V _{REF} + 0.1	—	V _{REF} - 0.175	V _{REF} + 0.175	0.2 × V _{CCIO}	0.8 × V _{CCIO}	8	-8

Switching Characteristics

This section provides performance characteristics of the Arria II GX and GZ core and periphery blocks for commercial grade devices. The following tables are considered final and are based on actual silicon characterization and testing. These numbers reflect the actual performance of the device under worst-case silicon process, voltage, and junction temperature conditions.

Transceiver Performance Specifications

Table 1–34 lists the Arria II GX transceiver specifications.

Table 1–34. Transceiver Specifications for Arria II GX Devices (Note 1) (Part 1 of 7)

Symbol/ Description	Condition	I3			C4			C5 and I5			C6			Unit	
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max		
Reference Clock															
Supported I/O Standards	1.2-V PCML, 1.5-V PCML, 2.5-V PCML, Differential LVPECL, LVDS, and HCSL														
Input frequency from REFCLK input pins	—	50	—	622.08	50	—	622.08	50	—	622.08	50	—	622.08	MHz	
Input frequency from PLD input	—	50	—	200	50	—	200	50	—	200	50	—	200	MHz	
Absolute V_{MAX} for a REFCLK pin	—	—	—	2.2	—	—	2.2	—	—	2.2	—	—	2.2	V	
Absolute V_{MIN} for a REFCLK pin	—	-0.3	—	—	-0.3	—	—	-0.3	—	—	-0.3	—	—	V	
Rise/fall time (2)	—	—	—	0.2	—	—	0.2	—	—	0.2	—	—	0.2	UI	
Duty cycle	—	45	—	55	45	—	55	45	—	55	45	—	55	%	
Peak-to-peak differential input voltage	—	200	—	2000	200	—	2000	200	—	2000	200	—	2000	mV	
Spread-spectrum modulating clock frequency	PCIe	30	—	33	30	—	33	30	—	33	30	—	33	kHz	

Table 1–34. Transceiver Specifications for Arria II GX Devices **(Note 1)** (Part 2 of 7)

Symbol/ Description	Condition	I3			C4			C5 and I5			C6			Unit
		Min	Typ	Max										
Spread-spectrum downspread	PCIe	—	0 to -0.5%	—	—									
On-chip termination resistors	—	—	100	—	—	100	—	—	100	—	—	100	—	Ω
V _{ICM} (AC coupled)	—	1100 ± 5%			1100 ± 5%			1100 ± 5%			1100 ± 5%			mV
V _{ICM} (DC coupled)	HCSL I/O standard for PCIe reference clock	250	—	550	250	—	550	250	—	550	250	—	550	mV
Transmitter REFCLK Phase Noise	10 Hz	—	—	-50	—	—	-50	—	—	-50	—	—	-50	dBc/Hz
	100 Hz	—	—	-80	—	—	-80	—	—	-80	—	—	-80	dBc/Hz
	1 KHz	—	—	-110	—	—	-110	—	—	-110	—	—	-110	dBc/Hz
	10 KHz	—	—	-120	—	—	-120	—	—	-120	—	—	-120	dBc/Hz
	100 KHz	—	—	-120	—	—	-120	—	—	-120	—	—	-120	dBc/Hz
	≥ 1 MHz	—	—	-130	—	—	-130	—	—	-130	—	—	-130	dBc/Hz
Transmitter REFCLK Phase Jitter (rms) for 100 MHz REFCLK (3)	10 KHz to 20 MHz	—	—	3	—	—	3	—	—	3	—	—	3	ps
R _{ref}	—	—	2000 ± 1%	—	—	2000 ± 1%	—	—	2000 ± 1%	—	—	2000 ± 1%	—	Ω
Transceiver Clocks														
Calibration block clock frequency (cal_blk_clk)	—	10	—	125	10	—	125	10	—	125	10	—	125	MHz

Table 1–34. Transceiver Specifications for Arria II GX Devices (*Note 1*) (Part 5 of 7)

Symbol/ Description	Condition	I3			C4			C5 and I5			C6			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
LTD lock time (11)	—	0	100	4000	0	100	4000	0	100	4000	0	100	4000	ns
Data lock time from rx_ freqlocked (12)	—	—	—	4000	—	—	4000	—	—	4000	—	—	4000	ns
Programmable DC gain	DC Gain Setting = 0	—	0	—	—	0	—	—	0	—	—	0	—	dB
	DC Gain Setting = 1	—	3	—	—	3	—	—	3	—	—	3	—	dB
	DC Gain Setting = 2	—	6	—	—	6	—	—	6	—	—	6	—	dB
Transmitter														
Supported I/O Standards	1.5-V PCML													
Data rate	—	600	—	6375	600	—	3750	600	—	3750	600	—	3125	Mbps
V _{OCM}	0.65 V setting	—	650	—	—	650	—	—	650	—	—	650	—	mV
Differential on-chip termination resistors	100-Ω setting	—	100	—	—	100	—	—	100	—	—	100	—	Ω
Return loss differential mode	PCIe	50 MHz to 1.25 GHz: -10dB												
	XAUJ	312 MHz to 625 MHz: -10dB 625 MHz to 3.125 GHz: -10dB/decade slope												
Return loss common mode	PCIe	50 MHz to 1.25 GHz: -6dB												
Rise time (2)	—	50	—	200	50	—	200	50	—	200	50	—	200	ps
Fall time	—	50	—	200	50	—	200	50	—	200	50	—	200	ps

Table 1–35. Transceiver Specifications for Arria II GZ Devices (Part 2 of 5)

Symbol/ Description	Conditions	–C3 and –I3 (1)			–C4 and –I4			Unit
		Min	Typ	Max	Min	Typ	Max	
Transceiver Clocks								
Calibration block clock frequency (cal_blk_clk)	—	10	—	125	10	—	125	MHz
fixedclk clock frequency	PCIe Receiver Detect	—	125	—	—	125	—	MHz
reconfig_clk clock frequency	Dynamic reconfiguration clock frequency	2.5/37.5 (4)	—	50	2.5/37.5 (4)	—	50	MHz
Delta time between reconfig_clks (5)	—	—	—	2	—	—	2	ms
Transceiver block minimum power-down (gxb_powerdown) pulse width	—	1	—	—	1	—	—	μs
Receiver								
Supported I/O Standards	1.4-V PCML, 1.5-V PCML, 2.5-V PCML, LVPECL, and LVDS							
Data rate (16)	—	600	—	6375	600	—	3750	Mbps
Absolute V _{MAX} for a receiver pin (6)	—	—	—	1.6	—	—	1.6	V
Operational V _{MAX} for a receiver pin	—	—	—	1.5	—	—	1.5	V
Absolute V _{MIN} for a receiver pin	—	-0.4	—	—	-0.4	—	—	V
Maximum peak-to-peak differential input voltage V _{ID} (diff p-p) before device configuration	—	—	—	1.6	—	—	1.6	V
Maximum peak-to-peak differential input voltage V _{ID} (diff p-p) after device configuration	V _{ICM} = 0.82 V setting	—	—	2.7	—	—	2.7	V
	V _{ICM} = 1.1 V setting (7)	—	—	1.6	—	—	1.6	V
Minimum differential eye opening at receiver serial input pins (8)	Data Rate = 600 Mbps to 5 Gbps Equalization = 0 DC gain = 0 dB	100	—	—	165	—	—	mV
	Data Rate > 5 Gbps Equalization = 0 DC gain = 0 dB	165	—	—	165	—	—	mV
V _{ICM}	V _{ICM} = 0.82 V setting	820 ± 10%			820 ± 10%			mV
	V _{ICM} = 1.1 V setting (7)	1100 ± 10%			1100 ± 10%			mV

Table 1–35. Transceiver Specifications for Arria II GZ Devices (Part 4 of 5)

Symbol/ Description	Conditions	–C3 and –I3 (1)			–C4 and –I4			Unit		
		Min	Typ	Max	Min	Typ	Max			
Transmitter										
Supported I/O Standards		1.5-V PCML								
Data rate (14)	—	600	—	6375	600	—	3750	Mbps		
V _{OCM}	0.65 V setting	—	650	—	—	650	—	mV		
Differential on-chip termination resistors	85-Ω setting	85 ± 15%			85 ± 15%			Ω		
	100-Ω setting	100 ± 15%			100 ± 15%			Ω		
	120-Ω setting	120 ± 15%			120 ± 15%			Ω		
	150-Ω setting	150 ± 15%			150 ± 15%			Ω		
Differential and common mode return loss	PCIe Gen1 and Gen2 (TX V _{OD} =4), XAUI (TX V _{OD} =6), HiGig+ (TX V _{OD} =6), CEI SR/LR (TX V _{OD} =8), SRIO SR (V _{OD} =6), SRIO LR (V _{OD} =8), CPRI LV (V _{OD} =6), CPRI HV (V _{OD} =2), OBSAI (V _{OD} =6), SATA (V _{OD} =4),	Compliant								
Rise time (15)	—	50	—	200	50	—	200	ps		
Fall time (15)	—	50	—	200	50	—	200	ps		
Intra-differential pair skew	—	—	—	15	—	—	15	ps		
Intra-transceiver block transmitter channel-to-channel skew	×4 PMA and PCS bonded mode Example: XAUI, PCIe ×4, Basic ×4	—	—	120	—	—	120	ps		
Inter-transceiver block transmitter channel-to-channel skew	×8 PMA and PCS bonded mode Example: PCIe ×8, Basic ×8	—	—	500	—	—	500	ps		
CMU0 PLL and CMU1 PLL										
Supported Data Range	—	600	—	6375	600	—	3750	Mbps		
p11_powerdown minimum pulse width (tp11_powerdown)	—	1			1			μs		
CMU PLL lock time from p11_powerdown de-assertion	—	—	—	100	—	—	100	μs		

Table 1–40. Transceiver Block Jitter Specifications for Arria II GX Devices (Note 1) (Part 3 of 10)

Symbol/ Description	Conditions	I3			C4			C5, I5			C6			Unit
		Min	Typ	Max										
PCIe Receiver Jitter Tolerance (4)														
Total jitter at 2.5 Gbps (Gen1)	Compliance pattern	> 0.6			> 0.6			> 0.6			> 0.6			UI
PCIe (Gen 1) Electrical Idle Detect Threshold (9)														
VRX-IDLE-DETDIFF (p-p)	Compliance pattern	65	—	175	65	—	175	65	—	175	65	—	175	mV
Serial RapidIO® (SRIO) Transmit Jitter Generation (5)														
Deterministic jitter (peak-to-peak)	Data Rate = 1.25, 2.5, 3.125 Gbps Pattern = CJPAT	—	—	0.17	—	—	0.17	—	—	0.17	—	—	0.17	UI
Total jitter (peak-to-peak)	Data Rate = 1.25, 2.5, 3.125 Gbps Pattern = CJPAT	—	—	0.35	—	—	0.35	—	—	0.35	—	—	0.35	UI
SRIO Receiver Jitter Tolerance (5)														
Deterministic jitter tolerance (peak-to-peak)	Data Rate = 1.25, 2.5, 3.125 Gbps Pattern = CJPAT	> 0.37			> 0.37			> 0.37			> 0.37			UI
Combined deterministic and random jitter tolerance (peak-to-peak)	Data Rate = 1.25, 2.5, 3.125 Gbps Pattern = CJPAT	> 0.55			> 0.55			> 0.55			> 0.55			UI
Sinusoidal jitter tolerance (peak-to-peak)	Jitter frequency = 22.1 KHz Data rate = 1.25, 2.5, 3.125 Gbps Pattern = CJPAT	> 8.5			> 8.5			> 8.5			> 8.5			UI
	Jitter frequency = 1.875 MHz Data rate = 1.25, 2.5, 3.125 Gbps Pattern = CJPAT	> 0.1			> 0.1			> 0.1			> 0.1			UI
	Jitter frequency = 20 MHz Data rate = 1.25, 2.5, 3.125 Gbps Pattern = CJPAT	> 0.1			> 0.1			> 0.1			> 0.1			UI
GIGE Transmit Jitter Generation (6)														
Deterministic jitter (peak-to-peak)	Pattern = CRPAT	—	—	0.14	—	—	0.14	—	—	0.14	—	—	0.14	UI

Table 1–40. Transceiver Block Jitter Specifications for Arria II GX Devices (Note 1) (Part 7 of 10)

Symbol/ Description	Conditions	I3			C4			C5, I5			C6			Unit
		Min	Typ	Max										
SSC modulation deviation at 1.5 Gbps (G1)	Compliance pattern	5700			5700			5700			5700			ppm
RX differential skew at 1.5 Gbps (G1)	Compliance pattern	80			80			80			80			ps
RX AC common mode voltage at 1.5 Gbps (G1)	Compliance pattern	150			150			150			150			mV
Total jitter tolerance at 3.0 Gbps (G2)	Compliance pattern	> 0.65			> 0.65			> 0.65			> 0.65			UI
Deterministic jitter tolerance at 3.0 Gbps (G2)	Compliance pattern	> 0.35			> 0.35			> 0.35			> 0.35			UI
SSC modulation frequency at 3.0 Gbps (G2)	Compliance pattern	33			33			33			33			kHz
SSC modulation deviation at 3.0 Gbps (G2)	Compliance pattern	5700			5700			5700			5700			ppm
RX differential skew at 3.0 Gbps (G2)	Compliance pattern	75			75			75			75			ps
RX AC common mode voltage at 3.0 Gbps (G2)	Compliance pattern	150			150			150			150			mV
Total jitter tolerance at 6.0 Gbps (G3)	Compliance pattern	> 0.60			> 0.60			> 0.60			> 0.60			UI
Random jitter tolerance at 6.0 Gbps (G3)	Compliance pattern	> 0.18			> 0.18			> 0.18			> 0.18			UI
SSC modulation frequency at 6.0 Gbps (G3)	Compliance pattern	33			33			33			33			kHz
SSC modulation deviation at 6.0 Gbps (G3)	Compliance pattern	5700			5700			5700			5700			ppm
RX differential skew at 6.0 Gbps (G3)	Compliance pattern	30			30			30			30			ps
RX AC common mode voltage at 6.0 Gbps (G3)	Compliance pattern	100			100			100			100			mV

Table 1–41. Transceiver Block Jitter Specifications for Arria II GZ Devices (Note 1), (2) (Part 5 of 7)

Symbol/ Description	Conditions	–C3 and –I3			–C4 and –I4			Unit
		Min	Typ	Max	Min	Typ	Max	
Sinusoidal jitter tolerance (peak-to-peak)	Jitter Frequency = 38.2 KHz Data rate = 6.375 Gbps Pattern = PRBS31 BER = 10^{-12}	> 0.5			—	—	—	UI
	Jitter Frequency = 3.82 MHz Data rate = 6.375 Gbps Pattern = PRBS31 BER = 10^{-12}	> 0.05			—	—	—	UI
	Jitter Frequency = 20 MHz Data rate = 6.375 Gbps Pattern = PRBS31 BER = 10^{-12}	> 0.05			—	—	—	UI
SDI Transmitter Jitter Generation (12)								
Alignment jitter (peak-to-peak)	Data rate = 1.485 Gbps (HD) Pattern = color bar Low-frequency roll-off = 100 KHz	0.2	—	—	0.2	—	—	UI
	Data rate = 2.97 Gbps (3G) Pattern = color bar Low-frequency roll-off = 100 KHz	0.3	—	—	0.3	—	—	UI
SDI Receiver Jitter Tolerance (12)								
Sinusoidal jitter tolerance (peak-to-peak)	Jitter frequency = 15 KHz Data rate = 2.97 Gbps (3G) Pattern = single line scramble color bar	> 2			> 2			UI
	Jitter frequency = 100 KHz Data rate = 2.97 Gbps (3G) Pattern = single line scramble color bar	> 0.3			> 0.3			UI
	Jitter frequency = 148.5 MHz Data rate = 2.97 Gbps (3G) Pattern = single line scramble color bar	> 0.3			> 0.3			UI
Sinusoidal jitter tolerance (peak-to-peak)	Jitter frequency = 20 KHz Data rate = 1.485 Gbps (HD) pattern = 75% color bar	> 1			> 1			UI
	Jitter frequency = 100 KHz Data rate = 1.485 Gbps (HD) Pattern = 75% color bar	> 0.2			> 0.2			UI
	Jitter frequency = 148.5 MHz Data rate = 1.485 Gbps (HD) Pattern = 75% color bar	> 0.2			> 0.2			UI
SAS Transmit Jitter Generation (13)								
Total jitter at 1.5 Gbps (G1)	Pattern = CJPAT	—	—	0.55	—	—	0.55	UI
Deterministic jitter at 1.5 Gbps (G1)	Pattern = CJPAT	—	—	0.35	—	—	0.35	UI
Total jitter at 3.0 Gbps (G2)	Pattern = CJPAT	—	—	0.55	—	—	0.55	UI

Table 1–41. Transceiver Block Jitter Specifications for Arria II GZ Devices (Note 1), (2) (Part 6 of 7)

Symbol/ Description	Conditions	–C3 and –I3			–C4 and –I4			Unit
		Min	Typ	Max	Min	Typ	Max	
Deterministic jitter at 3.0 Gbps (G2)	Pattern = CJPAT	—	—	0.35	—	—	0.35	UI
Total jitter at 6.0 Gbps (G3)	Pattern = CJPAT	—	—	0.25	—	—	0.25	UI
Random jitter at 6.0 Gbps (G3)	Pattern = CJPAT	—	—	0.15	—	—	0.15	UI
SAS Receiver Jitter Tolerance (13)								
Total jitter tolerance at 1.5 Gbps (G1)	Pattern = CJPAT	—	—	0.65	—	—	0.65	UI
Deterministic jitter tolerance at 1.5 Gbps (G1)	Pattern = CJPAT	—	—	0.35	—	—	0.35	UI
Sinusoidal jitter tolerance at 1.5 Gbps (G1)	Jitter frequency = 900 KHz to 5 MHz Pattern = CJTPAT BER = 1E-12	> 0.1			> 0.1			UI
CPRI Transmit Jitter Generation (14)								
Total jitter	E.6.HV, E.12.HV Pattern = CJPAT	—	—	0.279	—	—	0.279	UI
	E.6.LV, E.12.LV, E.24.LV, E.30.LV Pattern = CJPAT	—	—	0.35	—	—	0.35	UI
Deterministic jitter	E.6.HV, E.12.HV Pattern = CJPAT	—	—	0.14	—	—	0.14	UI
	E.6.LV, E.12.LV, E.24.LV, E.30.LV Pattern = CJPAT	—	—	0.17	—	—	0.17	UI
CPRI Receiver Jitter Tolerance (14)								
Total jitter tolerance	E.6.HV, E.12.HV Pattern = CJPAT	> 0.66			> 0.66			UI
Deterministic jitter tolerance	E.6.HV, E.12.HV Pattern = CJPAT	> 0.4			> 0.4			UI
Total jitter tolerance	E.6.LV, E.12.LV, E.24.LV, E.30.LV Pattern = CJPAT	> 0.65			> 0.65			UI
Deterministic jitter tolerance	E.6.LV, E.12.LV, E.24.LV, E.30.LV Pattern = CJPAT	> 0.37			> 0.37			UI
Combined deterministic and random jitter tolerance	E.6.LV, E.12.LV, E.24.LV, E.30.LV Pattern = CJPAT	> 0.55			> 0.55			UI
OBSAI Transmit Jitter Generation (15)								
Total jitter at 768 Mbps, 1536 Mbps, and 3072 Mbps	REFCLK = 153.6 MHz Pattern CJPAT	—	—	0.35	—	—	0.35	UI
Deterministic jitter at 768 MBps, 1536 Mbps, and 3072 Mbps	REFCLK = 153.6 MHz Pattern CJPAT	—	—	0.17	—	—	0.17	UI

Table 1–47. DSP Block Performance Specifications for Arria II GZ Devices (*Note 1*) (Part 2 of 2)

Mode	Resources Used	Performance			Unit
	Number of Multipliers	-3	-4		
Double mode	1	440	380	MHz	

Notes to Table 1–47:

- (1) Maximum is for fully pipelined block with **Round** and **Saturation** disabled.
- (2) Maximum for loopback input registers disabled, **Round** and **Saturation** disabled, and pipeline and output registers enabled.

Embedded Memory Block Specifications

Table 1–48 lists the embedded memory block specifications for Arria II GX devices.

Table 1–48. Embedded Memory Block Performance Specifications for Arria II GX Devices

Memory	Mode	Resources Used		Performance				Unit
		ALUTs	Embedded Memory	I3	C4	C5,I5	C6	
Memory Logic Array Block (MLAB)	Single port 64 × 10	0	1	450	500	450	378	MHz
	Simple dual-port 32 × 20 single clock	0	1	270	500	450	378	MHz
	Simple dual-port 64 × 10 single clock	0	1	428	500	450	378	MHz
M9K Block	Single-port 256 × 36	0	1	360	400	360	310	MHz
	Single-port 256 × 36, with the read-during-write option set to Old Data	0	1	250	280	250	210	MHz
	Simple dual-port 256 × 36 single CLK	0	1	360	400	360	310	MHz
	Single-port 256 × 36 single CLK, with the read-during-write option set to Old Data	0	1	250	280	250	210	MHz
	True dual port 512 × 18 single CLK	0	1	360	400	360	310	MHz
	True dual-port 512 × 18 single CLK, with the read-during-write option set to Old Data	0	1	250	280	250	210	MHz
	Min Pulse Width (clock high time)	—	—	900	850	950	1130	ps
	Min Pulse Width (clock low time)	—	—	730	690	770	920	ps

Periphery Performance

This section describes periphery performance, including high-speed I/O, external memory interface, and IOE programmable delay.

I/O performance supports several system interfaces, for example the high-speed I/O interface, external memory interface, and the PCI/PCI-X bus interface. I/O using SSTL-18 Class I termination standard can achieve up to the stated DDR2 SDRAM interfacing speed with typical DDR2 SDRAM memory interface setup. I/O using general purpose I/O (GPIO) standards such as 3.0, 2.5, 1.8, or 1.5 LVTT/LVCMOS are capable of typical 200 MHz interfacing frequency with 10pF load.



Actual achievable frequency depends on design- and system-specific factors. You should perform HSPICE/IBIS simulations based on your specific design and system setup to determine the maximum achievable frequency in your system.

High-Speed I/O Specification

Table 1–53 lists the high-speed I/O timing for Arria II GX devices.

Table 1–53. High-Speed I/O Specifications for Arria II GX Devices (Part 1 of 4)

Symbol	Conditions	I3		C4		C5,I5		C6		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
Clock										
f_{HSCLK_IN} (input clock frequency)—Row I/O	Clock boost factor, W = 1 to 40 (1)	5	670	5	670	5	622	5	500	MHz
f_{HSCLK_IN} (input clock frequency)—Column I/O	Clock boost factor, W = 1 to 40 (1)	5	500	5	500	5	472.5	5	472.5	MHz
f_{HSCLK_OUT} (output clock frequency)—Row I/O	—	5	670	5	670	5	622	5	500	MHz
f_{HSCLK_OUT} (output clock frequency)—Column I/O	—	5	500	5	500	5	472.5	5	472.5	MHz

Table 1–55. DPA Lock Time Specifications for Arria II Devices (Note 1), (2), (3)

Standard	Training Pattern	Number of Data Transitions in One Repetition of the Training Pattern	Number of Repetitions per 256 Data Transitions (4)	Maximum
SPI-4	00000000001111111111	2	128	640 data transitions
Parallel Rapid I/O	00001111	2	128	640 data transitions
	10010000	4	64	640 data transitions
Miscellaneous	10101010	8	32	640 data transitions
	01010101	8	32	640 data transitions

Notes to Table 1–55:

- (1) The DPA lock time is for one channel.
- (2) One data transition is defined as a 0-to-1 or 1-to-0 transition.
- (3) The DPA lock time stated in the table applies to both commercial and industrial grade.
- (4) This is the number of repetitions for the stated training pattern to achieve the 256 data transitions.

Figure 1–5 shows the LVDS soft-CDR/DPA sinusoidal jitter tolerance specification for Arria II GZ devices at a data rate less than 1.25 Gbps and all the Arria II GX devices.

Figure 1–5. LVDS Soft-CDR/DPA Sinusoidal Jitter Tolerance Specification for All Arria II GX Devices and for Arria II GZ Devices at a Data Rate less than 1.25 Gbps

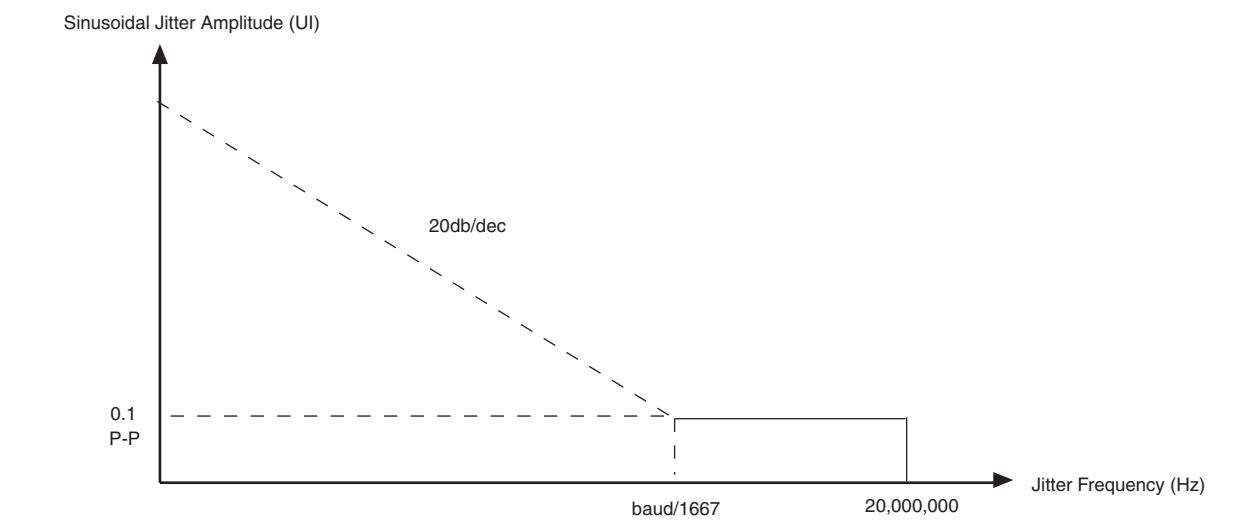


Table 1–57. External Memory Interface Specifications for Arria II GX Devices (Part 2 of 2)

Frequency Mode	Frequency Range (MHz)			Resolution (°)	DQS Delay Buffer Mode (1)	Number of Delay Chains
	C4	I3, C5, I5	C6			
5	270-410	270-380	270-320	36	High	10
6	320-450	320-410	320-370	45	High	8

Note to Table 1–57:

- (1) Low indicates a 6-bit DQS delay setting; high indicates a 5-bit DQS delay setting.

Table 1–58 lists the DLL frequency range specifications for Arria II GZ devices.

Table 1–58. DLL Frequency Range Specifications for Arria II GZ Devices

Frequency Mode	Frequency Range (MHz)		Available Phase Shift	DQS Delay Buffer Mode (1)	Number of Delay Chains
	-3	-4			
0	90-130	90-120	22.5°, 45°, 67.5°, 90°	Low	16
1	120-170	120-160	30°, 60°, 90°, 120°	Low	12
2	150-210	150-200	36°, 72°, 108°, 144°	Low	10
3	180-260	180-240	45°, 90°, 135°, 180°	Low	8
4	240-320	240-290	30°, 60°, 90°, 120°	High	12
5	290-380	290-360	36°, 72°, 108°, 144°	High	10
6	360-450	360-450	45°, 90°, 135°, 180°	High	8
7	470-630	470-590	60°, 120°, 180°, 240°	High	6

Note to Table 1–58:

- (1) Low indicates a 6-bit DQS delay setting; high indicates a 5-bit DQS delay setting.

Table 1–59 lists the DQS phase offset delay per stage for Arria II GX devices.

Table 1–59. DQS Phase Offset Delay Per Setting for Arria II GX Devices (Note 1), (2), (3)

Speed Grade	Min	Max	Unit
C4	7.0	13.0	ps
I3, C5, I5	7.0	15.0	ps
C6	8.5	18.0	ps

Notes to Table 1–59:

- (1) The valid settings for phase offset are -64 to +63 for frequency modes 0 to 3 and -32 to +31 for frequency modes 4 to 5.
(2) The typical value equals the average of the minimum and maximum values.
(3) The delay settings are linear.

Table 1-68. Glossary (Part 3 of 4)

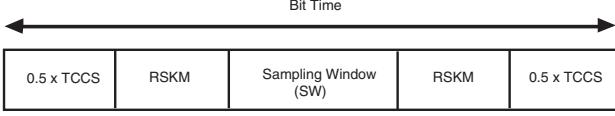
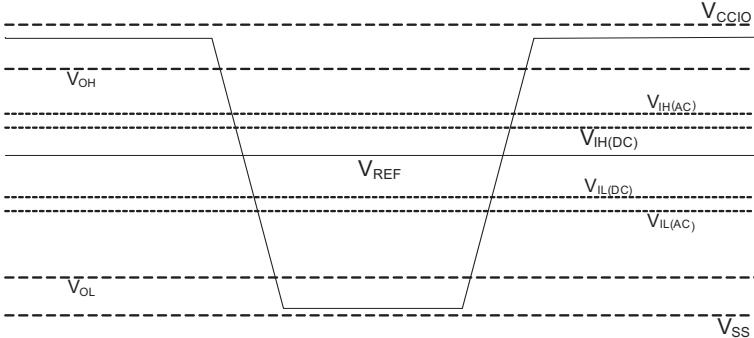
Letter	Subject	Definitions
	SW (sampling window)	The period of time during which the data must be valid in order to capture it correctly. The setup and hold times determine the ideal strobe position within the sampling window: <i>Timing Diagram</i> 
S	Single-ended Voltage Referenced I/O Standard	The JEDEC standard for SSTL and HSTL I/O standards define both the AC and DC input signal values. The AC values indicate the voltage levels at which the receiver must meet its timing specifications. The DC values indicate the voltage levels at which the final logic state of the receiver is unambiguously defined. After the receiver input has crossed the AC value, the receiver changes to the new logic state. The new logic state is then maintained as long as the input stays beyond the AC threshold. This approach is intended to provide predictable receiver timing in the presence of input waveform ringing: <i>Single-Ended Voltage Referenced I/O Standard</i> 
T	t_C	High-speed receiver and transmitter input and output clock period.
	TCCS (channel-to-channel-skew)	The timing difference between the fastest and slowest output edges, including t_{CO} variation and clock skew, across channels driven by the same PLL. The clock is included in the TCCS measurement (refer to the <i>Timing Diagram</i> figure under S in this table).
	t_{DUTY}	High-speed I/O block: Duty cycle on the high-speed transmitter output clock. Timing Unit Interval (TUI) The timing budget allowed for skew, propagation delays, and data sampling window. ($TUI = 1 / (\text{Receiver Input Clock Frequency Multiplication Factor}) = t_c/w$)
	t_{FALL}	Signal high-to-low transition time (80-20%)
	t_{INCCJ}	Cycle-to-cycle jitter tolerance on the PLL clock input.
	t_{OUTPJ_IO}	Period jitter on the general purpose I/O driven by a PLL.
	t_{OUTPJ_DC}	Period jitter on the dedicated clock output driven by a PLL.
	t_{RISE}	Signal low-to-high transition time (20-80%).

Table 1–68. Glossary (Part 4 of 4)

Letter	Subject	Definitions
U, V	$V_{CM(DC)}$	DC common mode input voltage.
	V_{ICM}	Input common mode voltage: The common mode of the differential signal at the receiver.
	V_{ID}	Input differential voltage swing: The difference in voltage between the positive and complementary conductors of a differential transmission at the receiver.
	$V_{DIF(AC)}$	AC differential input voltage: Minimum AC input differential voltage required for switching.
	$V_{DIF(DC)}$	DC differential input voltage: Minimum DC input differential voltage required for switching.
	V_{IH}	Voltage input high: The minimum positive voltage applied to the input which is accepted by the device as a logic high.
	$V_{IH(AC)}$	High-level AC input voltage.
	$V_{IH(DC)}$	High-level DC input voltage.
	V_{IL}	Voltage input low: The maximum positive voltage applied to the input which is accepted by the device as a logic low.
	$V_{IL(AC)}$	Low-level AC input voltage.
	$V_{IL(DC)}$	Low-level DC input voltage.
	V_{OCM}	Output common mode voltage: The common mode of the differential signal at the transmitter.
	V_{OD}	Output differential voltage swing: The difference in voltage between the positive and complementary conductors of a differential transmission at the transmitter.
W, X, Y, Z	W	High-speed I/O block: The clock boost factor.

Document Revision History

Table 1–69 lists the revision history for this chapter.

Table 1–69. Document Revision History (Part 1 of 2)

Date	Version	Changes
December 2013	4.4	Updated Table 1–34 and Table 1–35.
July 2012	4.3	<ul style="list-style-type: none"> ■ Updated the $V_{CCH_GXBL/R}$ operating conditions in Table 1–6. ■ Finalized Arria II GZ information in Table 1–20. ■ Added BLVDS specification in Table 1–32 and Table 1–33. ■ Updated input and output waveforms in Table 1–68.
December 2011	4.2	<ul style="list-style-type: none"> ■ Updated Table 1–32, Table 1–33, Table 1–34, Table 1–35, Table 1–40, Table 1–41, Table 1–54, and Table 1–67. ■ Minor text edits.
June 2011	4.1	<ul style="list-style-type: none"> ■ Added Table 1–60. ■ Updated Table 1–32, Table 1–33, Table 1–38, Table 1–41, and Table 1–61. ■ Updated the “Switching Characteristics” section introduction. ■ Minor text edits.